


<b>Search Notes</b>  	<b>Application/Control No.</b>  10676819	<b>Applicant(s)/Patent Under Reexamination</b>  WEDEL ET AL.
	<b>Examiner</b>  Chen, Qing	<b>Art Unit</b>  2191

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) -- See Search History Printout	5/31/2008	/QC/
717/100-103,110-113; 714/19; 715/530,531 (limited class search)	5/31/2008	/QC/
NPL Search (ACM) -- See Printout	5/31/2008	/QC/

INTERFERENCE SEARCH			
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